Program and Contents

June 19, 2014 (Thu)

Opening remark (10:30-10:35)

Plenary (10:35-11:55)

O1-1. (10:35-11:15) *- Tutorial talk -* ……………………………………………………….

Computer Insight into Processes Stimulated by Cluster Projectile Impacts

Z. Postawa (*Jagiellonian Univ.*)

O1-2. (11:15-11.55) *- Review talk -* ……………………………………………………….

Light at the End of the Tunnel: Novel Approaches to Achieving Significantly Improved Understanding of Secondary Ion Formation

K. Wittmaack (*Helmholtz Zentrum Munchen*)

Lunch (11:55-13:00)

Organic 1 (13:00-14:10)

O1-3. (13:00-13:30) *- Invited -* ………………………………………………………….………

The evaluation of peptide structures using ToF-SIMS and data analysis

S. Aoyagi (*Seikei Univ.*)

O1-4. (13:30-13:50) ……………………………………………………….....…………………

Mass scale calibration with quaternary ammonium ions for TOF-SIMS spectra measured by different TOF-SIMS instruments

S. Otomo (*Furukawa Electric*)

O1-5. (13:50-14:10) ……………………………………………………….....…………………

ToF-SIMS and PCA analysis of Oligomer distribution within Glass Fiber Reinforced Plastic

Y. Kajiwara (*Mitsubishi Gas Chemical*)

Break (14:10-14:30)

Organic 2 (14:30-15:40)

O1-6. (14:30-15:00) *- Invited -* ……………………………………………………….………

ToF SIMS as a navigation aid through the complex world of high throughput materials discovery

M. Alexander (*The Univ. of Nottingham*)

O1-7. (15:00-15:20) ……………………………………………………….....…………………

Measurements of secondary ions emitted from amino acid thin film with noble gases and molecular cluster ion

K. Moritani (*University of Hyogo*)

O1-8. (15:20-15:40) ……………………………………………………….....…………………

Possibilities and Limitations of Biological Analysis with novel Ar-GCIB SIMS Apparatus

M. Fujii (*Kyoto Univ.*)

Break (15:40-16:00)

Sponsored (16:00-17:20)

S1-1. (16:00-16:20) ……………………………………………………………………………

Towards New Applications with CAMECA SIMS Instruments

M. Schuhmacher (*CAMECA bu, AMETEK*)

S1-2. (16:20-16:40) ……………………………………………………………………………

Twenty-Five Years of Advances in TOF-SIMS Instrumentation and its Application

M. Terhost (*ION-TOF*)

S1-3. (16:40-17:00) ……………………………………………………………………………

TOF-SIMS apparatus having function of Laser-SNMS for nano-scale mass imaging

T. Kashiwagi (*TOYAMA*)

S1-4. (17:00-17:20) ……………………………………………………………………………

Recent progress of ion beam technologies in ULVAC-PHI

T. Miyayama (*ULVAC-PHI*)

Poster short presentation (17:20-18:00)

Poster session (18:00-19:00)

P-1. ……………………………………………………………………………………………

Comparison of Measurement Repeatability among Beam position alignment, Z-direction motion, and Auto-beam centering using a Cameca IMS 7f instrument

S. Miwa (*CAMECA bu, AMETEC*)

P-2. ……………………………………………………………………………………………

Reduction of phosphorus ion yield by electron beam irradiation under O_2 primary ion bombardment

Y. Hori (*Toshiba Nanoanalysis*)

P-3. ……………………………………………………………………………………………

Deconvolution of Depth Profiles of GaN-Based Light Emitting Diodes with Tunnel Junctions

Y. Nakata (*Toray Research Center*)

P-4. ……………………………………………………………………………………………

Light element analysis in oxide and nitride materials

I. Sakaguchi (*National Institute for Materials Science (NIMS)*)

P-5. ……………………………………………………………………………………………

Q-SIMS analysis of impurities in SnO_2 layer on glass substrate

T. Abe Sekine (*ASAHI GLASS*)

P-6. ……………………………………………………………………………………………

Hydrogen isotope fractionation of water by diffusion in silica glass

M. Kuroda (*Hokkaido Univ.*)

P-7. ……………………………………………………………………………………………

An investigation of depth resolution for dual-beam TOF-SIMS of Bi^+ and lower energy Cs^+ on depth profiling

J. Sameshima (*Toray Research Center*)

P-8. ……………………………………………………………………………………………

Helium depth profile of low energy ^4He implanted samples

K. Bajo (*Hokkaido Univ.*)

P-9. ……………………………………………………………………………………………

Organic Materials Analysis Using Different Primary Bi Ions in TOF-SIMS

R. Shishido (*Tohoku Univ.*)

P-10. ……………………………………………………………………………………………

Highly Sensitive Lipid Analysis and Imaging Mass Spectrometry with Cluster SIMS Apparatus

M. Fujii (*Kyoto Univ.*)

P-11. ……………………………………………………………………………………………

Mass accuracy dependence on energy and extractor voltage of analyzer in TOF-SIMS with single-stage reflection design

D. Kobayashi (*Asahi Glass*)

P-12. ……………………………………………………………………………………………

Atomic Level Analysis of Etched Carbon Fibers by the Scanning Atom Probe

M. Taniguchi (*Kanazawa Institute of Technology*)

P-13. ……………………………………………………………………………………………

Evaluation of Sample Shape after Evaporation in Laser Assisted Atom probe

M. Morita (*The Univ. of Tokyo*)

Social meeting (19:00-21:00)

June 20, 2014 (Fri)

Instrumentation / Complementary 1 (9:00-10:10)

O2-1. (9:00-9:30) *- Invited -* ……………………………………………………………………………

Atom Probe Tomography: Successes and Challenges

T. F. Kelly (*CAMECA*)

O2-2. (9:30-9:50) ……………………………………………………………………………………

Dependence of Quantitativity on Dopant Distribution in Silicon Provided by Atom Probe Tomography

T. Sasaki (*Toshiba Nanoanalysis*)

O2-3. (9:50-10:10) ……………………………………………………………………………………

Oxygen effect of Cr/Ni multilayered samples by resonance enhanced multiphoton ionization sputtered neutral mass spectrometry

S. Nishinomiya (*Nippon Steel & Sumitomo*)

Break (10:10-10:25)

Instrumentation / Complementary 2 (10:25-11:55)

O2-4. (10:25-10:55) *- Invited -* ……………………………………………………………………………

Laser desorption/ionization imaging mass spectrometry with ultra-high mass resolution mass spectrometer.

T. Satoh (*JEOL*)

O2-5. (10:55-11:15) ………………………………………………………… ……..………………..…

Time-of-Flight Secondary Ion Mass Spectrometry using an ionic-liquid primary ion beam generated by vacuum electrospray

Y. Fujiwara (*National Institute of Advanced Industrial Science and Technology* (*AIST*))

O2-6. (11:15-11:35) ………………………………………………………… ……..………………..…

In-situ GCIB Cross-section Imaging of Organic Materials

-Toward the Determination of Accurate Depth Distributions-

S. Iida (*ULVAC-PHI*)

O2-7. (11:35-11:55) ………………………………………………………… ……..………………..…

SIMS Depth Profiling by FIB Crater Wall Imaging of Organic and Inorganic Surfaces

D. Rading (*ION-TOF*)

Lunch (11:55-13:00)

Inorganic (13:00-14:40)

O2-8. (13:00-13:30) *- Invited -* ……………………………………………………………………

Light Elements and Related Materials Properties Revealed by TOF-SIMS

L. Zhang (*Institute of Metal Research, Chinese Academy of Science* (*CAS*))

O2-9. (13:30-14:00) *- Invited -* ……………………………………………………………………

From crater to crater: application of high resolution SIMS to Geosciences

K. Yi (*Korea Basic Science Institute*)

O2-10. (14:00-14:20) ……………………………………………………………………………

Development of high-precision analysis of multilayer structure

T. Shiramizu (*Mitsubishi Electric*)

Break (14:20-14:40)

Biomedical / Imaging (14:40-16:10)

O2-11. (14:40-15:10) *- Invited -* ……………………………………………………………………

Visualizing accumulation of photosynthetic products in plant using isotopic labeling and SIMS

M. Takeuchi (*The Univ. of Tokyo*)

O2-12. (15:10-15:30) ……………………………………………………………………………

Localization of ^{15}N-minodronate by Isotope Microscopy and Histochemical Assessment for the Biological Effects of Minodronate to Bone Cells in Mice

N. Amizuka (*Hokkaido Univ.*)

O2-13. (15:30-15:50) ……………………………………………………………………………

Molecular Analysis of Biological Tissues using Time-of-Flight Secondary Ion Mass Spectrometry (TOF-SIMS) and Gas Cluster Ion Beam (GCIB) sputtering

I. Ishizaki (*ULVAC-PHI*)

O2-14. (15:50-16:10) ……………………………………………………………………………

High Resolution Imaging Mass with Focused Ar Cluster Beam

J. Matsuo (*Kyoto Univ.*)

Closing remark (16:10)